

08-09-02

AF/2800

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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|-------------------|---|------------------|----------------|
| Applicant: | Ono et al. | Examiner: | J. Mitchell |
| Serial No.: | 09/842487 | Group Art Unit: | 2822 |
| Filed: | April 25, 2001 | Docket: | 10873.0447USD1 |
| Confirmation No.: | 7930 | Notice of Allow. | N/A |
| | | Date: | |
| Due Date: | August 7, 2002 | | |
| Title: | EDGE TESTING ELECTRODE FOR A SEMICONDUCTOR DEVICE | | |

CERTIFICATE UNDER 37 CFR 1.10:

"Express Mail" mailing label number: EV143559713US
Date of Deposit: August 7, 2002

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By: 

Name: John Junkers

Box AF
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Washington, D.C. 20231

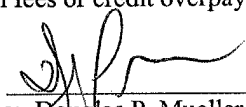
Sir:

We are transmitting herewith the attached:

- ☒ Return postcard
- ☒ Transmittal Sheet in duplicate containing Certificate of Mailing
- ☒ Amendment Including Version With Markings To Show Changes Made

Please consider this a PETITION FOR EXTENSION OF TIME for a sufficient number of months to enter these papers or any future reply, if appropriate. Please charge any additional fees or credit overpayment to Deposit Account No. 13-2725. A duplicate of this sheet is enclosed.

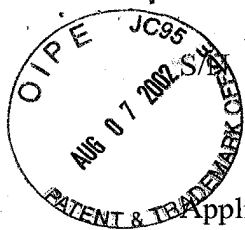
3200 IDS Center
80 South Eighth Street
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By: 
Name: Douglas P. Mueller
Reg. No.: 30,300
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09/842,487

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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|-------------|--|-----------------|---------------|
| Applicant: | ONO ET AL | Examiner: | J. MITCHELL |
| Serial No.: | 09/842,487 | Group Art Unit: | 2822 |
| Filed: | APRIL 25, 2001 | Docket No.: | 10873.447USD1 |
| Title: | EDGE TESTING ELECTRODE FOR A SEMICONDUCTOR DEVICE, (PREVIOUSLY: "SEMICONDUCTOR DEVICE") | | |

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By: 

Name: John Junkins

AMENDMENT AND RESPONSE

BOX AF
Commissioner for Patents
Washington, D.C. 20231

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Dear Sir:

In response to the final Office Action mailed May 7, 2002, Applicants provide the following amendments and remarks.

In the Specification

Please amend the title to read as follows:

EDGE TESTING ELECTRODE FOR A SEMICONDUCTOR DEVICE

In the Claims

Please cancel claim 24 without prejudice or disclaimer to the subject matter.

Please amend claim 22 to read as follows.

22. (twice amended) A semiconductor device manufactured by a wire bonding method using a metal wire, comprising a dedicated inspection region adapted to be contacted by a probe needle for inspection brought into contact therewith, and a region in which a metal ball formed at a tip of said metal wire by electric discharge is bonded to a terminal electrode formed on the semiconductor device, wherein a shape of the terminal electrode is rectangular, the shape having a portion protruded from a square that surrounds the region wherein the metal ball is bonded to the terminal electrode, the protruded portion being the dedicated inspection region adapted to be contacted by the probe needle.

